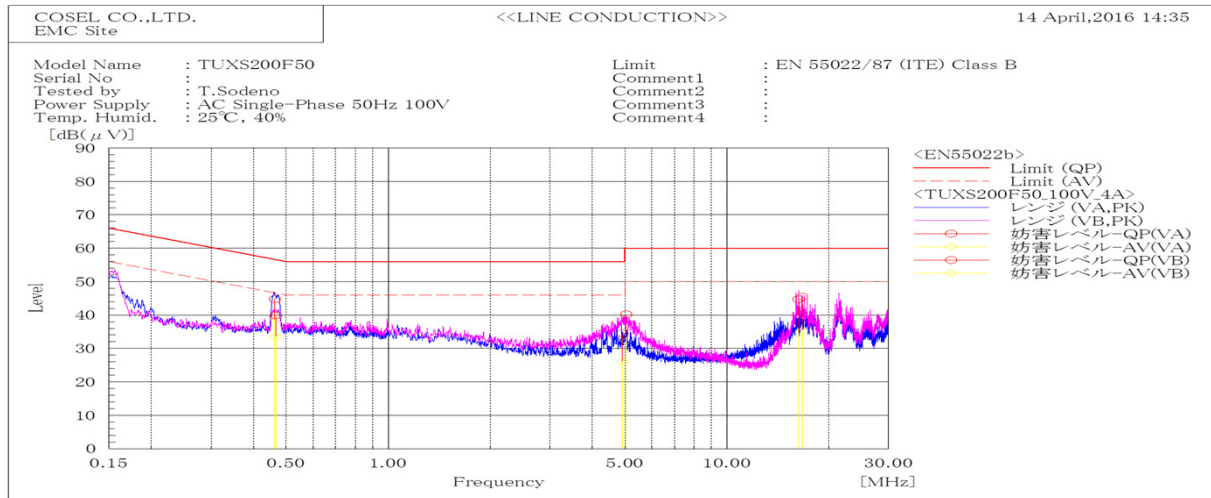
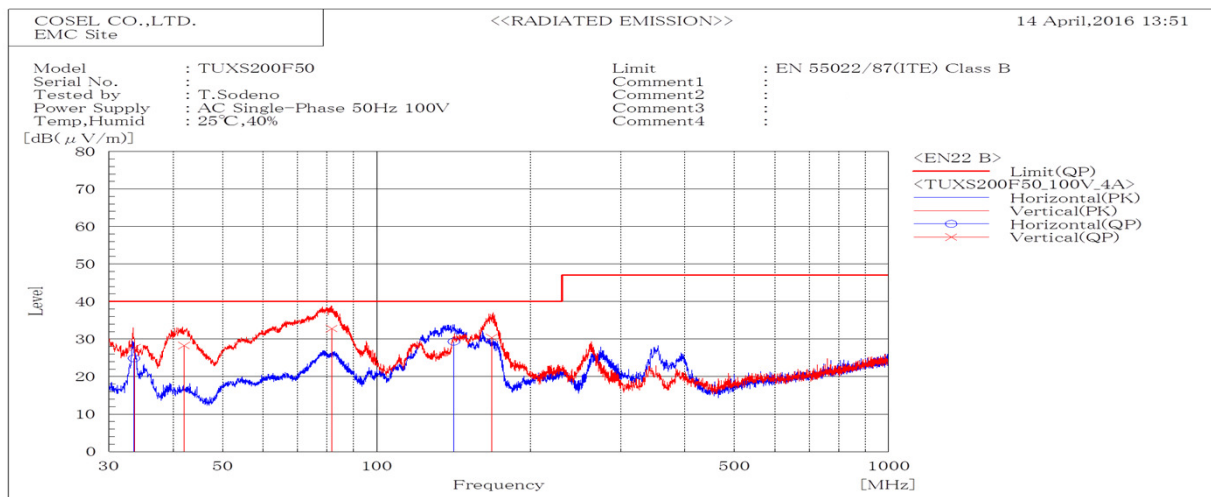


DATA SHEET		Date	14-Jun-16
Model	TUXS200F50	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sodeno



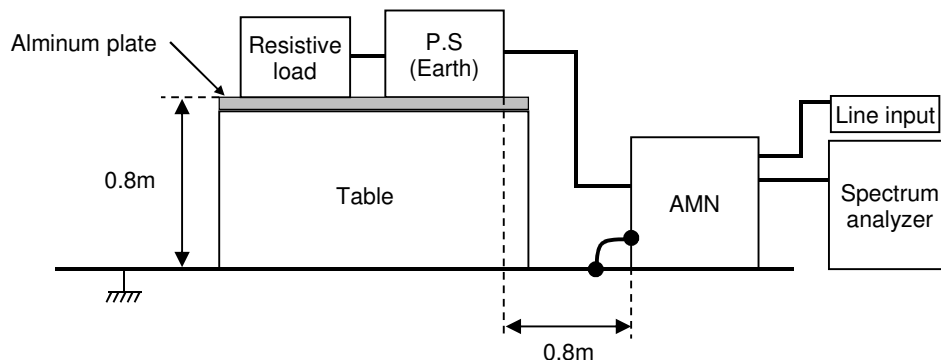
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46264		VA	24.8	18.8	20	44.8	38.8	56.6	46.6	11.8	7.8	Pass	
0.46604		VB	19.9	13.6	20	39.9	33.6	56.6	46.6	16.7	13	Pass	
4.91446		VA	14.2	5.8	20.3	34.5	26.1	56	46	21.5	19.9	Pass	
5.04172		VB	19.9	11.8	20.3	40.2	32.1	60	50	19.8	17.9	Pass	
16.28205		VB	23.9	13.6	20.8	44.7	34.4	60	50	15.3	15.6	Pass	
16.6587		VB	24.7	14.5	20.8	45.5	35.3	60	50	14.5	14.7	Pass	



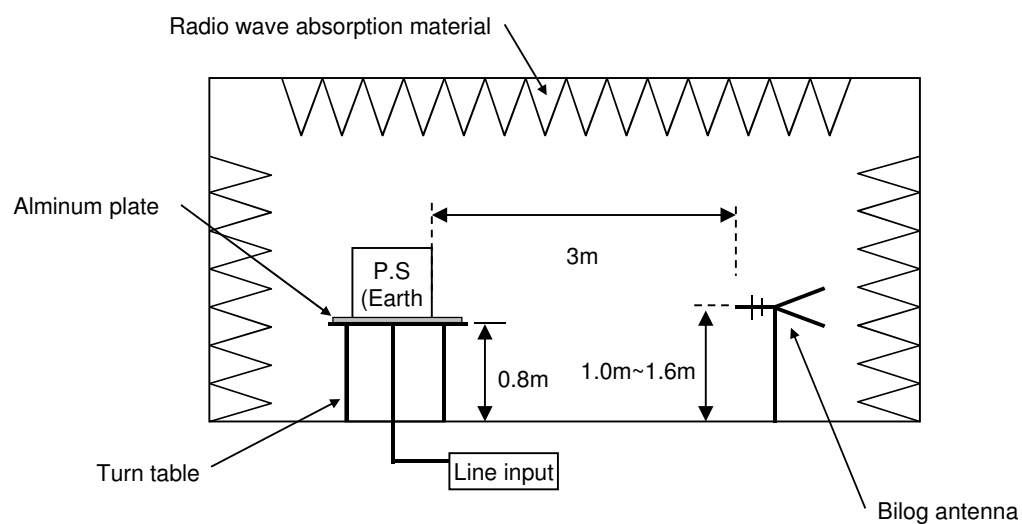
Frequency MHz	Polarization	Stability	Reading dB(μV)		Limit dB(μV/m)	Margin dB(μV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV						
33.556	H	Stable	24.8		40.0	15.2	Pass	144	66	
33.706	V	Stable	27.7		40.0	12.3	Pass	102	1	
42.050	V	Stable	28.3		40.0	11.7	Pass	101	251	
81.741	V	Stable	32.8		40.0	7.2	Pass	102	255	
141.439	H	Stable	29.4		40.0	10.6	Pass	159	187	
167.875	V	Stable	30.4		40.0	9.6	Pass	113	304	

DATA SHEET		Date	14-Jun-16
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sodeno

## 1. Line conduction



## 2. Radiated emission

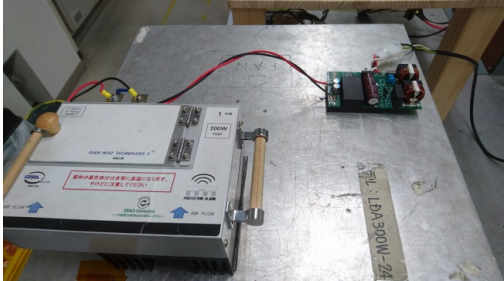


Test: EMI

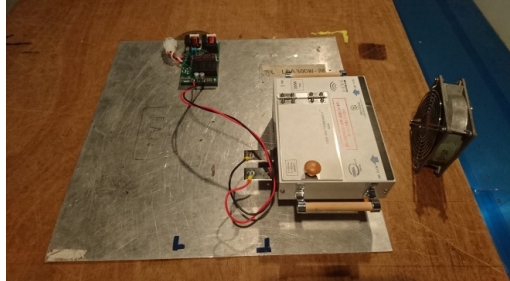
Model Name:TUXS200F50

○ Photographs of Test Set-Up

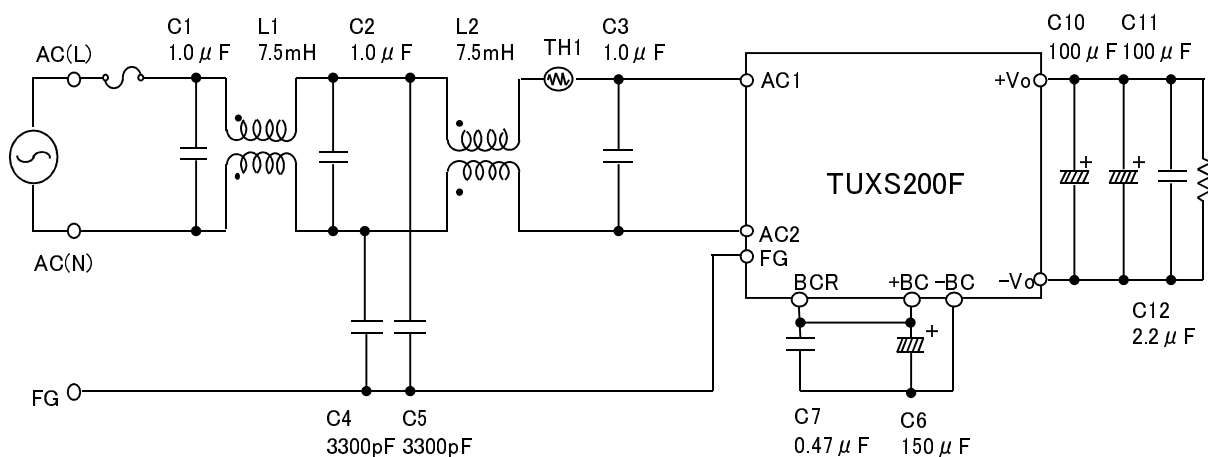
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



- L1,L2 : SCR22-060-1R0A075JH(NEC TOKIN)
- TH1 : 12D2-15LC(SEMITEC)
- C1,C2,C3 : LE105-MX(OKAYA)
- C4,C5 : DE1E3KX332M(MURATA)
- C6 : EKXJ421ELL151MM50S(Nippon Chemi-con)
- C7 : AFS450V474K(OKAYA)
- C10,C11 : PCR1J101MCL1GS(NICHICON)
- C12 : GRM31CR72A225K(MURATA)